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PCN Date: 23Nov10		Effective Date: 21Feb11	
Title: C8051T326/7, C8051T622/3 and CP2104 Series Product Revision F			
Originator: Pedro Pachuca	Phone: 512 532 5978	Dept: EMS	
Customer Contact: Kathy Haggar	Phone: 512-532-5261	Dept: Business Operations	
PCN Type: <input type="checkbox"/> Assembly <input type="checkbox"/> Discontinuance <input type="checkbox"/> Package <input type="checkbox"/> Test <input type="checkbox"/> Datasheet <input type="checkbox"/> Fabrication <input checked="" type="checkbox"/> Product Revision <input type="checkbox"/> Packing <input type="checkbox"/> Labeling <input type="checkbox"/> Location <input type="checkbox"/> Other			
Last Order Date: 21Feb11			
PCN Details			
Description of Change: Silicon Laboratories (Silicon labs) is pleased to announce revision F of the C8051T326/7, C8051T622/3 and CP2104 series product. This revision eliminates Rev A through E errata with the release of revision F.			
Reason for Change: Eliminate Rev A through E errata that had no available work around			
Impact on Form, Fit, Function, Quality, Reliability: There is no impact on Form, Fit, Quality and Reliability. The Function has changed to eliminate errata including repair of the output impedance drivers on the USB D+ and D- data lines. It is now nominally 36 Ω. In addition, the UART, GPIO and suspend signals are no longer driven low after power cycling the device. Revision F eliminates all known errata observed in rev A through E. The C8051T326/7, C8051T622/3 and CP2104 series revision F products are 100% functionally compatible with previous revisions.			

Product Identification:

This PCN applies to devices ordered using the following ordering part numbers:

Affected Ordering Part Numbers	
Old number	New Number
C8051T326-GM	No Change
C8051T622-GM	No Change
CP2104-A00-GM	CP2104-F03-GM
CP2104-B01-GM	
CP2104-C01-GM	
CP2104-D01-GM	
CP2104-E01-GM	
CP2104-E02-GM	
CP3000-E01-GM	CP3000-F01-GM

Note: Affected part numbers also include all custom parts made from the above listed based parts and tape and reel equivalents ("R" suffix)

Last Date of Unchanged Product: 21Feb11

Subsequent to the effective date of this PCN, Silicon labs will supply the new Rev F parts for all C8051T326/7, C8051T622/3 and CP2104 series product orders.

Qualification Samples:

Samples are available now. Please contact your local Silicon Laboratories sales representative to order samples. A list of authorized sales representatives may be found at www.silabs.com

Customer Early Acceptance Sign Off:

Customers may approve early PCN acceptance by completing the information below:

Early Acceptance Date:

Name:

Company:

Email your early Acceptance approval to: katherine.haggard@silabs.com

Qualification Data:

See Appendix A for Qualification Report

Appendix A: Qualification Report

C8051T622/CP210x Qualification Report



W7101F1 Product Qualification Plan and Report Rev. D

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C8051T622/CP210x Rev F, GSMC 0.18um Fabrication, Unisem QFN Assembly except as noted							
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group A - Accelerated Environment Stress Tests							
HAST	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>25	Q26334 Q25823 Q25877	0/81 0/80 0/80	1	3 lots 0/241	Pass
UHAIST	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q25825 Q25879 Q29462	0/80 0/81 0/77	1	3 lots 0/238	Pass
Temp Cycle	JA104 Cond C: -65°C to 150°C 500 cycles	3 lots, N=>25	Q25827 Q25878 Q29461	0/80 0/80 0/77	1	3 lots 0/237	Pass
HTSL	JA103 150°C, 1000hr	3 lots, N=>25	Q25817 Q25863 Q26485 Q26486	0/80 0/80 0/40 0/40	1	4 lots 0/240	Pass
Test Group B - Accelerated Lifetime Simulation Tests							
HTOL	JA108 125°C, Dynamic Vcc=3.6V, 1000 hours	3 lots, N=>77	Q26406 Q27166 Q27686	0/80 0/80 0/82		3 lots 0/242	Pass
LTOL	JA108 -10°C, Dynamic Vcc=3.6V, 1000 hours	1 lot, N=>32	Q25468	0/40		1 lots 0/40	Pass
ELFR	JA108 125°C, Dynamic Vcc=3.6V, 48 hours	3 lots, N=>500	Q27370 Q27897 Q29231	0/520 0/520 0/520		3 lots 0/1560	Pass
Test Group E - Electrical Verification							
ESD-HBM	JA114	1 lot, N=>3	Q29206				4kV
ESD-MM	JA115	1 lot, N=>3	Q29207				200V
ESD-CDM	JC101	1 lot, N=>3	Q29205				2kV
Latch Up	JESD78 ±200mA Overvoltage = 3.6V	1 lot, N=>6	Q29208 Q29204	85C 25C			Pass

Notes:

1. Devices subjected to moisture preconditioning at MSL1@260°C